

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 0mOhms
	Dwell Time: 10.0s	Offset: 85.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.00mA	Ramp Up: 10.0s
	Dwell Time: 60.0s	Ramp Down: 10.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000H000H0000000000000000 000000000	DUT Output: OFF		
4	Step 4: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.00mA	Ramp Up: 10.0s
	Dwell Time: 60.0s	Ramp Down: 10.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H00000000000000000 000000000	DUT Output: OFF		
5	Step 5: Prompt			
6	Step 6: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 30.0s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: UL544NP		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:000H00000000000000000000 000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 10.0s	Neutral: CLOSED	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:000H00000000000000000000 000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

	Scanner 1:000HH0000000000000000000000000000 0000000000			
9	Step 9: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
10	Step 10: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: UL544NP		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: UL544NP		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: UL544NP		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
13	Step 13: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
14	Step 14: Prompt			
15	Step 15: Line Leakage			
	Leakage-HI: 5000.00uA	Leakage-LO: 0.01uA	Voltage-HI: 270.0V	Voltage-LO: 264.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: UL544NP		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	

	Batch Test: OFF			
	Scanner 1:000HH00000000000H0000HL L00000000			

Vapr Vue Parameter Specification

Vapr Vue Parameter Specification

10	Step 10: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
12	Step 12: Prompt			
13	Step 13: Line Leakage	Patient^Leakage^		
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
14	Step 14: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOOOOOOOOOOOOOOOOOOOOOO 0000000000			
15	Step 15: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOOOOOOOOOOOOOOOOOOOO 0000000000			
16	Step 16: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			

Vapr Vue Parameter Specification

	Scanner 1:HOOOHOooooooooooooooo OOOOOOOO			
17	Step 17: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOooooooooooooooo OOOOOOOO			
18	Step 18: Prompt			
19	Step 19: Line Leakage	MOAP^Patient^Leakage^		
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOoooooooooooooHOOOHL LOOOOOOO			
20	Step 20: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: CLOSED	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOoooooooooooooHOOOHL LOOOOOOO			
21	Step 21: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOoooooooooooooHOOOHL LOOOOOOO			
22	Step 22: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOoooooooooooooHOOOHL LOOOOOOO			

Versapoint Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 39.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 39.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:2			
4	Step 4: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 39.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:3			
5	Step 5: AC Withstand			
	Voltage: 1500V	HI-Limit T: 5.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 60.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0000000H000000000000000000000000 0000000000	DUT Output: OFF		
6	Step 6: Prompt			
7	Step 7: AC Withstand			
	Voltage: 4000V	HI-Limit T: 2.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 60.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0000H0H000000000000000000000000 0000000000	DUT Output: OFF		
8	Step 8: AC Withstand			
	Voltage: 5000V	HI-Limit T: 2.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 10.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0000H0H000000000000000000000000 0000000000	DUT Output: OFF		
9	Step 9: Prompt			

Versapoint Parameter Specification

10	Step 10: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 5.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 100.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
13	Step 13: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 100.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
14	Step 14: Prompt			
15	Step 15: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 5.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHOOOOOOOOOOOOOOOOOOOOOO 0000000000			
16	Step 16: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			

Versapoint Parameter Specification

	Scanner 1:HOOOHoooooooooooooooooooo 00000000			
17	Step 17: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHoooooooooooooooooooo 00000000			
18	Step 18: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHoooooooooooooooooooo 00000000			

VAPR 3 Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 39.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 39.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:2			
4	Step 4: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 39.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:3			
5	Step 5: AC Withstand			
	Voltage: 1500V	HI-Limit T: 5.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 30.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0000000H00000000000000000000000000000000	DUT Output: OFF		
6	Step 6: Prompt			
7	Step 7: AC Withstand	5000^Volt^Ap^to^L/N		
	Voltage: 5000V	HI-Limit T: 2.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 10.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:LOOOOOHOH000000000000000000000000	DUT Output: OFF		
8	Step 8: Prompt			
9	Step 9: Line Leakage	Earth^Leakage^		
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00			

10	Step 10: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
12	Step 12: Prompt			
13	Step 13: Line Leakage	Patient^Leakage^		
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
14	Step 14: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHooooooooooooooo0000000000 0000000000			
15	Step 15: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:HOOOHooooooooooooooo0000000000 0000000000			
16	Step 16: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			

VAPR 3 Parameter Specification

	Scanner I:HOOOHOoooooooooooooooOoooo			
17	Step 17: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:HOOOHOoooooooooooooooOoooo			
18	Step 18: Prompt			
19	Step 19: Line Leakage	MOAP^Patient^Leakage^		
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:HOOOHOooooooooooooOHOOOHLL			
20	Step 20: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: CLOSED	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:HOOOHOooooooooooooOHOOOHLL			
21	Step 21: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:HOOOHOooooooooooooOHOOOOLH			
22	Step 22: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 3.0s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Probe-LO	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:HOOOHOooooooooooooOHOOOOLH			

PSI TEC III Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 5.0s	Offset: 90.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:2			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.50mA	Ramp Up: 10.0s
	Dwell Time: 60.0s	Ramp Down: 10.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000HH0000000000000000 000000000	DUT Output: OFF		
4	Step 4: Prompt			
5	Step 5: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000 000000000			
6	Step 6: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000 000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000 000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

PSI TEC III Parameter Specification

	Scanner 1:000HH00000000000000000000000000 0000000000			
9	Step 9: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
10	Step 10: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
12	Step 12: Prompt			
13	Step 13: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
14	Step 14: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
15	Step 15: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	

	Batch Test: OFF			
	Scanner 1:000HHoooooooooooooooooooo 0ooooooooo			
16	Step 16: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HHoooooooooooooooooooo 0ooooooooo			
17	Step 17: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HHoooooooooooooooooooo 0ooooooooo			
18	Step 18: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:000HHoooooooooooooooooooo 0ooooooooo			

CVDT Parameter Specification				
1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 1.00A	Voltage: 8.00V	High Limit: 600mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 0.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:3			
3	Step 3: DC Withstand			
	Voltage: 2545V	HI-Limit: 5000.0uA	LO-Limit: 0.0uA	Ramp Up: 6.0s
	Dwell Time: 1.0s	Ramp Down: 6.0s	Charge-Lo: 0.00uA	Auto Charge-LO: OFF
	Arc Sense: 5	Ramp-HI: OFF	Arc Detect: OFF	Continuity: OFF
	Offset: 0.00mA	Batch Test: OFF		
	Scanner 1:0000000H0H0000000000000000000000 0000000000	DUT Output: OFF		
4	Step 4: DC Withstand			
	Voltage: 2600V	HI-Limit: 100.0uA	LO-Limit: 0.0uA	Ramp Up: 6.0s
	Dwell Time: 2.0s	Ramp Down: 6.0s	Charge-Lo: 0.00uA	Auto Charge-LO: OFF
	Arc Sense: 5	Ramp-HI: OFF	Arc Detect: OFF	Continuity: OFF
	Offset: 0.00mA	Batch Test: OFF		
	Scanner 1:0000000H0H0000000000000000000000 0000000000	DUT Output: OFF		

OVS1 Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 1.00A	Voltage: 8.00V	High Limit: 600mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 0.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:3			
3	Step 3: DC Withstand			
	Voltage: 2545V	HI-Limit: 5000.0uA	LO-Limit: 0.0uA	Ramp Up: 6.0s
	Dwell Time: 1.0s	Ramp Down: 6.0s	Charge-Lo: 0.00uA	Auto Charge-LO: OFF
	Arc Sense: 5	Ramp-HI: OFF	Arc Detect: OFF	Continuity: OFF
	Offset: 0.00mA	Batch Test: OFF		
	Scanner 1:0000000HH0000000000000000 000000000	DUT Output: OFF		
4	Step 4: DC Withstand			
	Voltage: 2600V	HI-Limit: 100.0uA	LO-Limit: 0.0uA	Ramp Up: 6.0s
	Dwell Time: 2.0s	Ramp Down: 6.0s	Charge-Lo: 0.00uA	Auto Charge-LO: OFF
	Arc Sense: 5	Ramp-HI: OFF	Arc Detect: OFF	Continuity: OFF
	Offset: 0.00mA	Batch Test: OFF		
	Scanner 1:0000000HH0000000000000000 000000000	DUT Output: OFF		

MINI Vac Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 15.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 10.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.00mA	Ramp Up: 10.0s
	Dwell Time: 20.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H00000000000000000 000000000	DUT Output: OFF		
4	Step 4: Prompt			
5	Step 5: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: UL544NP		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:000000000000000000000000 000000000			
6	Step 6: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 10.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:000H00000000000000000000 000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000H00000000000000000000 000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

	Scanner 1:000HH00000000000000000000000000 000000000			
9	Step 9: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 000000000			

Micro French IEC Parameter Specification				
1	Step 1: Prompt			
2	Step 2: AC Withstand			
	Voltage: 500V	HI-Limit T: 1.00mA	LO-Limit T: 0.00mA	Ramp Up: 10.0s
	Dwell Time: 60.0s	Ramp Down: 10.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000H000H000000000000000000000000 0000000000	DUT Output: OFF		
3	Step 3: Prompt			
4	Step 4: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 80mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 39.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:2			
5	Step 5: Prompt			
6	Step 6: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 30.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000H0000000000000000000000000000 0000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 5.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000H0000000000000000000000000000 0000000000			
9	Step 9: Prompt			
10	Step 10: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V

Attachment 1 to PRC089785 Associated Research Electrical Safety Test Equipment Installation Qualification Protocol Completion Report
Micro HandPiece Parameter Specification

	Delay Time: 5.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-I UL2601-I		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 000000000			

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 10.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.00mA	Ramp Up: 10.0s
	Dwell Time: 20.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000HH0000000000000000 000000000	DUT Output: OFF		
4	Step 4: Prompt			
5	Step 5: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:000000000000000000000000 000000000			
6	Step 6: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 10.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000 000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000 000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 10000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

Attachment 1 to PRC089785 Associated Research Electrical Safety Test Equipment Installation Qualification Protocol Completion Report
MESE1 Smoke Evacuator Parameter Specification

	Scanner 1:000HH00000000000000000000000000 000000000			
9	Step 9: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 000000000			

MegaPower 1000 Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: Prompt			
4	Step 4: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
5	Step 5: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 10.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
6	Step 6: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

	Scanner 1:000H0000000000000000000000000000 00000000			
9	Step 9: Prompt			
10	Step 10: Line Leakage			
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 250.0V	Voltage-LO: 230.0V
	Delay Time: 10.0s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000H0000000000000000000000000000 00000000			

GEN11 Parameter Specification

	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:00000000000000000000000000000000 0000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:00000000000000000000000000000000 0000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner I:00000000000000000000000000000000 0000000000			

GEN11 wih Power Cord Parameter Specification

GENTI WiFi Power Cord Parameter Specification				
Step	Parameter	Value	Test Result	Notes
1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 53.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: Prompt			
4	Step 4: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 1mOhms
	Dwell Time: 6.0s	Offset: 53.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
5	Step 5: AC Withstand			
	Voltage: 1776V	HI-Limit T: 10.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 1.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H0000000000000000000000000	DUT Output: OFF		
6	Step 6: Prompt			
7	Step 7: AC Withstand	5000^Volt^Ap^to^L/N		
	Voltage: 4000V	HI-Limit T: 2.00mA	LO-Limit T: 0.10mA	Ramp Up: 5.0s
	Dwell Time: 1.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0OLOOHOH0000000000000000000000000	DUT Output: OFF		
8	Step 8: Prompt			
9	Step 9: Line Leakage	Earth^Leakage^		
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:000000000000000000000000000000000			
10	Step 10: Line Leakage	Patient^Leakage^		
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	

GEN11 with Power Cord Parameter Specification

	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 54.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: Prompt			
4	Step 4: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 1mOhms
	Dwell Time: 6.0s	Offset: 54.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
5	Step 5: AC Withstand			
	Voltage: 1776V	HI-Limit T: 10.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 1.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0000000H000000000000000000000000	DUT Output: OFF		
6	Step 6: Prompt			
7	Step 7: AC Withstand	5000^Volt^Ap^to^L/N		
	Voltage: 4000V	HI-Limit T: 2.00mA	LO-Limit T: 0.10mA	Ramp Up: 5.0s
	Dwell Time: 1.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:00LOOH0H000000000000000000000000	DUT Output: OFF		
8	Step 8: Prompt			
9	Step 9: Line Leakage	Earth^Leakage^		
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000			
10	Step 10: Line Leakage	Patient^Leakage^		
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	

GEN11 with Power Cord Parameter Specification

	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 000000000			
13	Step 13: Prompt			
14	Step 14: Line Leakage	Earth^Leakage^		
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:OOHOHOOOOOOOOOOOOOOOOOOOOOO 000000000			
15	Step 15: Line Leakage	Patient^Leakage^		
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:OOHOHOOOOOOOOOOOOOOOOOOOO 000000000			
16	Step 16: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:OOHOHOOOOOOOOOOOOOOOOOO 000000000			
17	Step 17: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN

GEN11 with Power Cord Parameter Specification

	Measurement Device: IEC601-1 UL2601-1	Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s
	Batch Test: OFF		
	Scanner I:OOHOHooooooooooooooo0000000000000000 000000000		

GEATT Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 6.0s	Offset: 54.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: Prompt			
4	Step 4: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 1mOhms
	Dwell Time: 6.0s	Offset: 54.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
5	Step 5: AC Withstand			
	Voltage: 1776V	HI-Limit T: 10.00mA	LO-Limit T: 0.10mA	Ramp Up: 0.1s
	Dwell Time: 1.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H0H00000000000000000000000	DUT Output: OFF		
6	Step 6: Prompt			
7	Step 7: AC Withstand	5000^Volt^Ap^to^L/N		
	Voltage: 4000V	HI-Limit T: 2.00mA	LO-Limit T: 0.10mA	Ramp Up: 5.0s
	Dwell Time: 1.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0OLOOH0H000000000000000000000000	DUT Output: OFF		
8	Step 8: Prompt			
9	Step 9: Line Leakage	Earth^Leakage^		
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000			
10	Step 10: Line Leakage	Patient^Leakage^		
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	

GEN11 Parameter Specification

	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 000000000			
11	Step 11: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 000000000			
13	Step 13: Prompt			
14	Step 14: Line Leakage	Earth^Leakage^		
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00HOHO00000000000000000000000000 000000000			
15	Step 15: Line Leakage	Patient^Leakage^		
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00HOHO00000000000000000000000000 000000000			
16	Step 16: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:00HOHO00000000000000000000000000 000000000			
17	Step 17: Line Leakage			
	Leakage-HI: 50.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN

GEN11 Parameter Specification

	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:OOHOHOoooooooooooooooooooooooo 000000000			

FMS VUE with HipotParameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:2			
3	Step 3: Prompt			
4	Step 4: AC Withstand			
	Voltage: 2500V	HI-Limit T: 1.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 2.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000HH0000000000000000 000000000	DUT Output: OFF		
5	Step 5: Prompt			
6	Step 6: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000 000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 30.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000 000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000 000000000			
9	Step 9: Prompt			
10	Step 10: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V

FMS VUE with Hipot Parameter Specification

Delay Time: 15.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
Active Link: OFF	Memory Send: %sMI	Dwell Time: 1.0s	
Batch Test: OFF			
Scanner 1:000HH0000000000000000000000 00000000			

FMS VUE II with Hipot Parameter Specification

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 6.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 2.0s	Arc Sense: 5	HI-Limit R: 6.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H00000000000000000 000000000	DUT Output: OFF		
4	Step 4: Insulation Resistance			
	Voltage: 500V	HI-Limit: 20000.0MOhms	LO-Limit: 2.0MOhms	Ramp Up: 0.1s
	Delay Time: 1.0s	Ramp Down: 0.0s	Charge LO: 0.00	Auto Charge LO: OFF
	Dwell Time: 5.0s			
	Batch Test: OFF			
	Scanner 1:000000H00000000000000000 000000000	DUT Output: OFF		
5	Step 5: AC Withstand			
	Voltage: 1500V	HI-Limit T: 3.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 2.0s	Arc Sense: 5	HI-Limit R: 6.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000H000H0000000000000000 000000000	DUT Output: OFF		
6	Step 6: Insulation Resistance			
	Voltage: 500V	HI-Limit: 20000.0MOhms	LO-Limit: 2.0MOhms	Ramp Up: 0.1s
	Delay Time: 1.0s	Ramp Down: 0.0s	Charge LO: 0.00	Auto Charge LO: OFF
	Dwell Time: 5.0s			
	Batch Test: OFF			
	Scanner 1:000H000H0000000000000000 000000000	DUT Output: OFF		
7	Step 7: Prompt			
8	Step 8: AC Withstand			
	Voltage: 1500V	HI-Limit T: 3.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 2.0s	Arc Sense: 5	HI-Limit R: 6.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000L0H0H0000000000000000 000000000	DUT Output: OFF		

9	Step 9: Insulation Resistance			
	Voltage: 500V	HI-Limit: 20000.0MOhms	LO-Limit: 2.0MOhms	Ramp Up: 0.1s
	Delay Time: 1.0s	Ramp Down: 0.0s	Charge LO: 0.00	Auto Charge LO: OFF
	Dwell Time: 5.0s			
	Batch Test: OFF			
	Scanner 1:000LOHOOHOHOOOOOOOOOOOOOOOOOO 000000000	DUT Output: OFF		
10	Step 10: Prompt			
11	Step 11: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 30.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 000000000			
13	Step 13: Line Leakage			
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 000000000			
14	Step 14: Prompt			
15	Step 15: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 15.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 000000000			

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 37.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:2			
3	Step 3: Prompt			
4	Step 4: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
5	Step 5: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 30.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
6	Step 6: Line Leakage			
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			
7	Step 7: Prompt			
8	Step 8: Line Leakage			
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 260.0V
	Delay Time: 15.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH00000000000000000000000000 0000000000			

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 6.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 2.0s	Arc Sense: 5	HI-Limit R: 6.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H00000000000000000000000000000000	DUT Output: OFF		
4	Step 4: Insulation Resistance			
	Voltage: 500V	HI-Limit: 20000.0MOhms	LO-Limit: 2.0MOhms	Ramp Up: 0.1s
	Delay Time: 1.0s	Ramp Down: 0.0s	Charge LO: 0.00	Auto Charge LO: OFF
	Dwell Time: 5.0s			
	Batch Test: OFF			
	Scanner 1:000000H00000000000000000000000000000000	DUT Output: OFF		
5	Step 5: AC Withstand			
	Voltage: 1500V	HI-Limit T: 3.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 2.0s	Arc Sense: 5	HI-Limit R: 6.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000H000H00000000000000000000000000000000	DUT Output: OFF		
6	Step 6: Insulation Resistance			
	Voltage: 500V	HI-Limit: 20000.0MOhms	LO-Limit: 2.0MOhms	Ramp Up: 0.1s
	Delay Time: 1.0s	Ramp Down: 0.0s	Charge LO: 0.00	Auto Charge LO: OFF
	Dwell Time: 5.0s			
	Batch Test: OFF			
	Scanner 1:000H000H00000000000000000000000000000000	DUT Output: OFF		
7	Step 7: Prompt			
8	Step 8: AC Withstand			
	Voltage: 1500V	HI-Limit T: 3.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 2.0s	Arc Sense: 5	HI-Limit R: 6.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000L0H0000000000000000000000000000000000	DUT Output: OFF		

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FMS VUE II With HIpot Parameter Specification

9	Step 9: Insulation Resistance			
	Voltage: 500V	HI-Limit: 20000.0MOhms	LO-Limit: 2.0MOhms	Ramp Up: 0.1s
	Delay Time: 1.0s	Ramp Down: 0.0s	Charge LO: 0.00	Auto Charge LO: OFF
	Dwell Time: 5.0s			
	Batch Test: OFF			
	Scanner 1:000LOHOHOOOOOOOOOOOOOOOO 000000000	DUT Output: OFF		

1	Step 1: Prompt		
2	Step 2: Ground Bond		
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms
	Dwell Time: 1.0s	Offset: 23.00mOhms	Auto Offset: OFF
	DualCHEK: OFF		Frequency: 60 Hz
	Batch Test: OFF		
	Scanner: 1:1		
3	Step 3: Prompt		
4	Step 4: Line Leakage		
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s
	Batch Test: OFF		
	Scanner 1:00000000000000000000000000000000 0000000000		
5	Step 5: Line Leakage		
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V
	Delay Time: 30.0s	Neutral: CLOSED	Reverse: OFF
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s
	Batch Test: OFF		
	Scanner 1:000HH00000000000000000000000000 0000000000		
6	Step 6: Line Leakage		
	Leakage-HI: 10.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: OFF
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s
	Batch Test: OFF		
	Scanner 1:000HH00000000000000000000000000 0000000000		
7	Step 7: Prompt		
8	Step 8: Line Leakage		
	Leakage-HI: 100.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V
	Delay Time: 15.0s	Neutral: CLOSED	Reverse: OFF
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s
	Batch Test: OFF		
	Scanner 1:000HH00000000000000000000000000 0000000000		

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 1.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:0			

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 3.0s	Offset: 40.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.01mA	Ramp Up: 3.0s
	Dwell Time: 60.0s	Ramp Down: 3.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:0000000H00000000000000000000000000000000	DUT Output: OFF		
4	Step 4: Insulation Resistance			
	Voltage: 500V	HI-Limit: 0.0MOhms	LO-Limit: 2.0MOhms	Ramp Up: 1.0s
	Delay Time: 1.0s	Ramp Down: 1.0s	Charge LO: 0.00	Auto Charge LO: OFF
	Dwell Time: 5.0s			
	Batch Test: OFF			
	Scanner 1:0000000H00000000000000000000000000000000	DUT Output: OFF		
5	Step 5: Prompt			
6	Step 6: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 12.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:00			
7	Step 7: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:00			
8	Step 8: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:00			

9	Step 9: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
10	Step 10: Prompt			
11	Step 11: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 12.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
12	Step 12: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
13	Step 13: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
14	Step 14: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
15	Step 15: Prompt			
16	Step 16: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 12.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 15.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 0mOhms
	Dwell Time: 10.0s	Offset: 85.00mOhms	Auto Offset: ON	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.00mA	Ramp Up: 10.0s
	Dwell Time: 20.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000HH000000000000000000000000	DUT Output: OFF		
4	Step 4: Prompt			
5	Step 5: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: UL544NP		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00			
6	Step 6: Line Leakage			
	Leakage-HI: 200.00uA	Leakage-LO: 0.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 10.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:000HH000000000000000000000000000000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH000000000000000000000000000000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

	Scanner 1:000HH0000000000000000000000000000 0000000000			
9	Step 9: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			

TESTS: Single Earthed Parameter of Connection				
Step	Parameter Settings			
1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 10.0s	Offset: 23.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:1			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.00mA	Ramp Up: 10.0s
	Dwell Time: 20.0s	Ramp Down: 0.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H0000000000000000000000000	DUT Output: OFF		
4	Step 4: Prompt			
5	Step 5: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000			
6	Step 6: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 10.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 3.0s	
	Batch Test: OFF			
	Scanner 1:000H0000000000000000000000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000H0000000000000000000000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 10000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V	Voltage-LO: 230.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

		MESE1 Smoke Evacuator Parameter Specification	
	Scanner 1:000HH00000000000000000000000000 0000000000		
9	Step 9: Line Leakage		
	Leakage-HI: 1000.00uA	Leakage-LO: 50.00uA	Voltage-HI: 270.0V
	Delay Time: 1.8s	Neutral: OPEN	Reverse: ON
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: ON	Memory Send: %sM1	Dwell Time: 1.0s
	Batch Test: OFF		
	Scanner 1:000HH00000000000000000000000000 0000000000		

ASPII Parameter Specification

Attachment 1 to PRC089785 Associated Research Electrical Safety Test Equipment Installation Qualification Protocol Completion Report

1	Step 1: Prompt			
2	Step 2: Ground Bond			
	Current: 25.00A	Voltage: 8.00V	High Limit: 100mOhms	Low Limit: 25mOhms
	Dwell Time: 5.0s	Offset: 73.00mOhms	Auto Offset: OFF	Frequency: 60 Hz
	DualCHEK: OFF			
	Batch Test: OFF			
	Scanner 1:2			
3	Step 3: AC Withstand			
	Voltage: 1500V	HI-Limit T: 10.00mA	LO-Limit T: 0.50mA	Ramp Up: 10.0s
	Dwell Time: 60.0s	Ramp Down: 10.0s	Arc Sense: 5	HI-Limit R: 10.00mA
	LO-Limit R: 0.00mA	Frequency: 60 Hz	Arc Detect: OFF	Continuity: OFF
	Auto Offset: OFF	Offset: 0.00mA		
	Batch Test: OFF			
	Scanner 1:000000H00000000000000000000000000000000	DUT Output: OFF		
4	Step 4: Prompt			
5	Step 5: Line Leakage			
	Leakage-HI: 6000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 125.0V	Voltage-LO: 0.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 0.5s	
	Batch Test: OFF			
	Scanner 1:00			
6	Step 6: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000H000000000000000000000000000000000000			
7	Step 7: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			
	Scanner 1:000H000000000000000000000000000000000000			
8	Step 8: Line Leakage			
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V	Voltage-LO: 105.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: CLOSED
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s	
	Batch Test: OFF			

ASPII Parameter Specification

Attachment 1 to PRC089785 Associated Research Electrical Safety Test Equipment Installation Qualification Protocol Completion Report

	Scanner 1:000HH0000000000000000000000000000 0000000000		
9	Step 9: Line Leakage		
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: OFF
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s
	Batch Test: OFF		
	Scanner 1:000HH0000000000000000000000000000 0000000000		
10	Step 10: Line Leakage		
	Leakage-HI: 300.00uA	Leakage-LO: 0.00uA	Voltage-HI: 115.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: OFF	Memory Send: %sM1	Dwell Time: 1.0s
	Batch Test: OFF		
	Scanner 1:000HH0000000000000000000000000000 0000000000		

9	Step 9: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
10	Step 10: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Ground To Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:00000000000000000000000000000000 0000000000			
11	Step 11: Prompt			
12	Step 12: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 12.0s	Neutral: CLOSED	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
13	Step 13: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
14	Step 14: Line Leakage			
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			
15	Step 15: Line Leakage			
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V	Voltage-LO: 230.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON	Ground: OPEN
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line	
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s	
	Batch Test: OFF			
	Scanner 1:000HH0000000000000000000000000000 0000000000			

			FMS Duo Parameter Specification
16	Step 16: Prompt		
17	Step 17: Line Leakage		
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V
	Delay Time: 12.0s	Neutral: CLOSED	Reverse: OFF
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s
	Batch Test: OFF		
	Scanner 1:000HHoooooooooooo0000000000 000000000		
18	Step 18: Line Leakage		
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V
	Delay Time: 0.5s	Neutral: CLOSED	Reverse: ON
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s
	Batch Test: OFF		
	Scanner 1:000HHoooooooooooo0000000000 000000000		
19	Step 19: Line Leakage		
	Leakage-HI: 500.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: OFF
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s
	Batch Test: OFF		
	Scanner 1:000HHoooooooooooo0000000000 000000000		
20	Step 20: Line Leakage		
	Leakage-HI: 1000.00uA	Leakage-LO: 0.00uA	Voltage-HI: 245.0V
	Delay Time: 0.5s	Neutral: OPEN	Reverse: ON
	Measurement Device: IEC601-1 UL2601-1		Probe: Probe-HI to Line
	Active Link: ON	Memory Send: %sM1	Dwell Time: 15.0s
	Batch Test: OFF		
	Scanner 1:000HHoooooooooooo0000000000 000000000		